Prof. Makris received the Diploma degree in computer engineering and informatics from the University of Patras, Patras, Greece, in 1995, and the M.S. and Ph.D. degrees in computer science and engineering from the University of California at San Diego, La Jolla, CA, USA, in 1998 and 2001, respectively. After spending over a decade on the faculty of Electrical Engineering and of Computer Science at Yale University, he joined the University of Texas at Dallas, where he is currently a Professor of Electrical Engineering, leading the Trusted and Reliable Architectures (TRELA) Research Laboratory. His current research focuses on the applications of machine learning and statistical analysis in the development of trusted and reliable integrated circuits and systems, with particular emphasis in the analog/RF domain, and has been supported by NSF, SRC, ARO, DARPA, SRC, Boeing, Intel, LSI, IBM, and Texas Instruments. Prof. Makris serves as an Associate Editor of the IEEE Transactions on Information Forensics and Security, the IEEE Design and Test Periodical and the Springer Journal of Electronic Testing Theory and Applications, and served as a Guest Editor of the IEEE Transactions on Computers and the IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems. He also served as the General Chair (2016) as well as the Program Chair (2013-2014) of the IEEE VLSI Test Symposium, and as the Program Chair (2010-2012) of the Test Technology Educational Program (TTEP) of the IEEE Computer Society Test Technology Technical Council (TTTC). He also serves regularly as a Topic Coordinator and/or Program Committee Member for several IEEE and ACM conferences in the areas of VLSI Testing, Hardware Security, and Design Automation. Prof. Makris was the recipient of the 2006 Sheffield Distinguished Teaching Award, as well as Best Paper Awards from the 2013 Design Automation and Test in Europe Conference and the 2015 IEEE VLSI Test Symposium.